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By:

THOMAS M. GALGANO

Date: May 21, 2007



PATENT

DOCKET NO.: 1834-2

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICANT : KIM ET AL.
SERIAL NO. : 10/541,876
FILED : JULY 8, 2005
TITLE : APPARATUS AND METHOD FOR MEASUREMENT OF FILM
THICKNESS USING IMPROVED FAST FOURIER
TRANSFORMATION
EXAMINER : MICHAEL A. LYONS
ART UNIT NO. : 2877

AMENDMENT IN REPLY TO OFFICE ACTION

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

In response to the Office Action dated December 19, 2006, please amend the
above-identified application as follows:

05/29/2007 SFELEKE1 00000004 10541876

01 FC:2252

225.00 OP

Amendments to the Specification are reflected on page 3 of this paper.

Amendments to the Drawings are reflected on page 4 of this paper.

Amendments to the Abstract are reflected on page 5 of this paper.

Amendments to the Claims are reflected on page 6 of this paper.

Remarks/Arguments begin on page 9 of this paper.